A. OTHER JUNCTIONS

B. SEMICONDUCTOR HETEROJUNCTIONS --

MOLECULES AT INTERFACES:

• ORGANIC PHOTOVOLTAIC BULK HETEROJUNCTION

• DYE-SENSITIZED SOLAR CELL

March 20, 2014 The University of Toledo, Department of Physics and Astronomy SSARE, PVIC

Principles and Varieties of Solar Energy (PHYS 4400)

1. Poisson's equation:

$$\frac{\partial \bar{E}}{dx} = \frac{\rho}{\varepsilon} = \frac{q}{\varepsilon} \left(p(x) - n(x) - N_A^- + N_D^+ \right)$$

2. Transport equations:

$$J_n = q\mu_n n(x)\vec{E} + qD_n \frac{dn(x)}{dx}$$
$$J_p = q\mu_p p(x)\vec{E} - qD_p \frac{dp(x)}{dx}$$

3. Continuity equations: General conditions

 $\frac{dn}{dt} = \frac{1}{q} \frac{\partial J_n}{\partial x} - (U - G)$

$$\frac{dp}{dt} = \frac{1}{q} \frac{\partial J_p}{\partial x} + (U - G) \qquad \qquad \frac{1}{q} \frac{\partial J_p}{\partial x} = -(U - G)$$

A note on units: looking at the Continuity equation(s) – units for dn/dt are cm⁻³s⁻¹. Units for (1/q)(dJ/dx) work out to be: $(C^{-1})(C s^{-1} cm^{-2})(cm^{-1}) = cm^{-3}s^{-1}$.

Under thermal equilibrium and steady state conditions

$$\frac{1}{q}\frac{\partial J_n}{\partial x} = (U - G)$$

where U and G are the recombination and generation rates in the particular material and depend on the details of the device and may also depend on distance.



p-n junction and semiconductor physics review

Poisson's Equation

$$\frac{d\hat{E}}{dx} = \frac{\rho}{\varepsilon} = \frac{q}{\varepsilon}(p - n + N_D^+ - N_A^-)$$

Straightforward definitions:

E is the electric field

ho is the charge density

q is the magnitude of the electron charge

p is the concentration of free holes

n is the concentration of free electrons

 N_D^+ is the concentration of ionized donor atoms (recall that <u>donors</u> donate electrons, leaving them <u>positively</u> charged)

 N_A^- is the concentration of ionized acceptor atoms (recall that acceptors accept electrons, leaving them <u>negatively</u> charged)



Semiconductor physics review

Density of States in Conduction and Valence Band (parabolic band approximation)

$$N_{C}(E) = \frac{m_{n}^{3/2} \sqrt{2}}{\pi^{2} \hbar^{3}} \sqrt{E - E_{C}}$$
$$N_{V}(E) = \frac{m_{p}^{3/2} \sqrt{2}}{\pi^{2} \hbar^{3}} \sqrt{E_{V} - E}$$

Look at units: (note that 1 J = 1 kg-m²-s⁻², and [*h*] = m²kg s⁻¹)

$$\frac{kg^{3/2}J^{1/2}s^3}{m^6kg^3} = \frac{kg^{3/2}kg^{1/2}s^3m}{m^6kg^3s} = kg^{-1}s^2m^{-5} = J^{-1}m^{-3}$$

Fermi function (state occupation probability)

$$f(E) = \frac{1}{1 + \exp\left(\frac{E - E_F}{kT}\right)}$$

Junctions

Reading assignment:

- Work Function: <u>http://en.wikipedia.org/wiki/Work_function</u>
- Electron Affinity (solid state physics): <u>http://en.wikipedia.org/wiki/Electron_affinity</u>
 - Vacuum Level: <u>http://en.wikipedia.org/wiki/Vacuum_level</u>
 - Fermi Energy: <u>http://en.wikipedia.org/wiki/Fermi_energy</u>
 - Fermi Level: <u>http://en.wikipedia.org/wiki/Fermi_level</u>

Work Function: potential required to remove the least tightlybound electron:

$$\Phi_w = E_{vac} - E_F$$

Work function equals the electron affinity in metals.

Bases for effective fields at junctions





In (a) a difference in the work function has given rise to a gradient in the vacuum level and hence an electrostatic field, $\frac{1}{a}\nabla E_{\text{vac}}$.

In (b) a difference in the electron affinity due to a compositional gradient creates an effective field, $-\frac{1}{q}\nabla\chi$, seen as a gradient in the conduction band edge.

In (c) a field due to a gradient in the effective conduction band density of states, $-\frac{kT}{q} \ln \nabla N_c$, is driving electrons to the right. This term cannot be depicted on this diagram as it represents a gradient in the *free* energy rather than potential energy: carriers are driven thermodynamically in the direction of increasing availability of states.

Charge-separation mechanisms

- gradient in the vacuum level or work function
- \rightarrow electrostatic field (e.g., doping level)
- gradient in electron affinity \rightarrow effective field
- gradient in the band gap → effective field
- gradient in the band DOS → effective field

Metal-semiconductor junctions: Schottky-barrier



Fig. 5.4. (a) Band profiles of n-type semiconductor and metal in isolation. (b) Band profile of the semiconductor-metal junction in equilibrium.

- In contact: electrons flow from semiconductor to metal, resulting in a layer of positive fixed charge in the semiconductor, near the surface (and a negative image charge on the metal); Fermi levels equilibrate;
- Potential difference drops in the semiconductor (space charge, and/or depletion, region);
- Result is a lower resistance pathway for holes than for electrons

Metal-semiconductor junctions: Schottky-barrier (cont.)



Fig. 5.5. Band profile of the semiconductor-metal junction under illumination at open circuit. The accumulation of photogenerated electrons in the n-type semiconductor raises the electron Fermi level and generates a photovoltage, V.

- Under illumination, holes flow to the right, and electrons accumulate in the semiconductor;
- Fermi level shifts up in the semiconductor (accumulation of electrons);
- Result is a photovoltage

Metal-semiconductor junctions: Schottky-barrier (cont.)



Fig. 5.6. (a) Schematic current-voltage characteristic of a Schottky barrier junction in the dark. A, B and C mark points on the curve where the device is at reverse bias, equilibrium and forward bias; (b) A: band profile of an *n*-type semiconductor-metal Schottky barrier at reverse bias. The only current is due to minority carrier (hole) drift across the depleted barrier region. B: band profile at equilibrium. The currents due to electron diffusion and hole drift cancel out. C: band profile at forward bias. The current due to electron diffusion is greatly increased as the barrier height is reduced, and the net current changes sign.

Metal-semiconductor junctions: Schottky-barrier (cont.)



Fig. 5.7. Band profile of the p-type semiconductor-metal junction (a) at equilibrium and (b) under illumination at open circuit.

- In contact: holes flow from the semiconductor to the metal, resulting in a layer of negative fixed charge in the semiconductor near the surface (and a positive image charge on the metal); Fermi levels equilibrate;
- Potential difference drops in the semiconductor (space charge, and/or depletion, region);
- Result is a lower resistance pathway for electrons (to the metal) than for holes
- Under illumination, electrons flow into the metal from the semiconductor

Metal-semiconductor junctions: Ohmic contact

Φ



Fig. 5.8. Ohmic metal-semiconductor contacts for (a) an n-type semiconductor and (b) a p-type semiconductor. In each case the difference in work functions is supplied by the build up of majority carriers in an accumulation layer near the interface. An accumulation layer is generally narrow compared to a depletion layer because of the higher density of charges and stronger electric field.

We can draw the following conclusions from the above discussion:

- a charge separating field is established at the interface between two materials of different work function
- the junction will develop a photovoltage provided that it presents a barrier to majority carrier currents
- the photovoltage is related to the difference in work functions
- Note that at Ohmic contact provides a low resistance pathway for majority carrier from the semiconductor to the metal

Organic PV: Bulk heterojunction



Organic PV: simplified BH structure



Organic PV: interface energetics



Dye-sensitized TiO₂ solar cell



"Reaction": $S + hv \rightarrow S^* \iff S^+ + e^-$

M. Grätzel / Journal of Photochemistry and Photobiology C: Photochemistry Reviews 4 (2003) 145–153

Dye-sensitized TiO₂ solar cell





Binding of dye (monolayer) to TiO_2 through carboxylate groups; photon absorption results in metal-to-ligand charge transfer (MLCT) and rapid injection (<20 fs) of the e⁻ into the TiO_2 CB.

M. Grätzel / Journal of Photochemistry and Photobiology C: Photochemistry Reviews 4 (2003) 145–153

transfer sensitizer in dye-sensitized solar cells.

Bid on a PV project, using different technologies

Analysis of the LCOE for a rooftop PV system, including a summary of the materials science of the technology

- 1. Thin film silicon (Abril)
- 2. CdTe (Jeff)
- 3. c-Si (Ryan)

Issues to be considered:

• <u>Materials science</u>: describe the key properties of the materials used to make the solar PV modules. What are the values for efficiency, stability over time, performance vs. module temperature, power:weight ratio (W_p/kg), module size, and toxicity concerns.

- <u>Rooftop area</u>: 600 square feet at a slope of 30° limited area.
- <u>Cost factors</u>: cost per W_p of modules; cost of inverter, total system capacity (W_p at STC), racking and labor costs.
- <u>Calculation of the LCOE</u>: based on all costs incurred (include M&O) and all energy produced (include your projected electricity costs and any SREC value).

PowerPoint presentation:

- 20 min. plus 5 min Q&A
- Completely referenced, with appropriate figures
- Original content/work (new ideas and ways of presenting data and results)
- Presentations on April 22